Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/667,372	TAKAHASHI, TOSHIHIDE	
Examiner	Art Unit	
Anabel M. Ton	2875	

SEARCHED				
Class	Subclass	Date	Examiner	
362	546,549	8/5/2005	АТ	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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